

Notice of References Cited	Application/Control No. 10/634,001		Applicant(s)/Patent Under Reexamination CHANG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,665,203	09-1997	Lee et al.	438/585
	B	US-6,656,832	12-2003	Pan et al.	438/627
	C	US-6,284,665	09-2001	Lill et al.	438/710
	D	US-6,440,756	08-2002	Shohet et al.	438/4
	E	US-6,566,264	05-2003	Cave et al.	438/689
	F	US-6,194,323	02-2001	Downey et al.	438/717
	G	US-5,679,606	10-1997	Wang et al.	438/763
	H	US-6,759,337	07-2004	Aronowitz et al.	438/706
	I	US-6,184,158	02-2001	Shufflebotham et al.	438/788
	J	US-6,251,792	06-2001	Collins et al.	438/710
	K	US-6,143,625	11-2000	Chen et al.	438/435
	L	US-6,372,654	04-2002	Tokashiki, Ken	438/712
	M	US-6,620,713	09-2003	Arghavani et al.	438/585

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	The Handbook of Plasma Processing Technology - Fundamentals, Etching, Deposition, and Surface Interactions, edited by Rossnagel, page 198, 1990			
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,242,536	09-1993	Schoenborn, Philippe	438/714
*	B	US-5,665,203	09-1997	Lee et al.	438/585
*	C	US-6,620,575	09-2003	Kim et al.	430/314
*	D	US-6,093,332	07-2000	Winniczek et al.	216/2
*	E	US-6,902,681	06-2005	Nallan et al.	216/67
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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